Diffraction and Instruments for Neutron Diffraction

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Who am I?

• University education (solid-state chemist)

- Chemistry Degree (with supplementary Bio-chemistry)
- D. Phil. in Solid State Chemistry "Fullerene Intercalation Compounds"
- 7 years Post Doctoral experience
 - High-pressure, zeolites, magnetic materials, superconductors, pigments, isotopes

Instrument scientist (powder diffraction)

- 5 years as co-responsible for D20 at ILL, Grenoble
- 2.5 years responsible E9 at HZB, Berlin
- 5.5 years responsible for powder diffraction at ESS, Lund
- Since Jan 2017 senior instrument scientist at ISIS, Didcot
- Since May 2013 Adjunct Professor in Neutron Scattering at CTH, Göteborg

• Research interests

- Hydrogenous materials and neutrons
- In-situ sample environment development
- Materials research
- Instrument development
- Neutron diffraction community development



Outline

- Neutron scattering methods & science
- Key concepts
- Diffraction measurements
- Aspects influencing diffractometer design
 - Source type
 - Q range
 - Q resolution
 - Detectors
 - Availability
 - CW or TOF?
 - Powder or single crystal?
- Instrument examples
 - CW powder
 - CW single crystal
 - TOF powder
 - TOF single crystal



Neutron scattering & science



Neutron scattering methods







Why diffraction?

- Diffraction is the tool we use to determine structure
- Structure determines the physical properties of a material
- To tailor physical properties we must understand structure

Most diffraction measurements use powders. Why?

- Many materials are difficult to make as single crystals
- Most practical uses require bulk materials
- Functional materials may require non-perfect crystals or mixed systems
- Phase transitions destroy or fracture single crystals



Uses of diffraction

- Check purity of a sample
- Identify known phases
- Identify new phases
- Collect data for structural analysis
- Follow phase transitions
- Construct phase diagrams (T, P, B, etc)
- Study chemical processes in situ
- Monitor particle sizes
- Analyse residual stress within materials
- Process control
- Etc...



Key concepts



Miller indices / planes

Unit cell planes can be defined by the notation called Miller indices. The Miller index is given as a hkl number where *h*, *k*, and *l* are reciprocals of the plane with the *x*, *y*, and *z* axes.

To obtain the Miller indices of a given plane requires the following steps:



Step 1. The plane in question is placed on a unit cell.Step 2. Find its intercepts with each of the crystal axes.Step 3. The reciprocal of the intercepts are taken.Step 4. Multiply by a scalar to get a ratio of integers.



Miller indices

d₀₁₀











(111)

(010)

(011)

The higher the Miller index the less distance there is between equivalent planes, dividing the unit cell into ever smaller slices



For higher symmetry cells interplane distances are identical $d_{001} = d_{010} = d_{100}$ for cubic





- Constructive interference occurs when the waves reflected from adjacent scattering planes remain in phase – diffraction peak is observed
- The path difference travelled by waves between adjacent planes must be an integral multiple of the wavelength

$n\lambda = 2dsin\theta$





- A sphere of radius $1/\lambda$ (2-D projection shown above)
- Potential diffracted X-rays/neutrons can be along any radius from the centre of the sphere to the circumference (including out of plane in the projection above). This represents the experimental possibilities (λ, possible 2θs)





- Alternative view of the crystal structure (hk0 plane illustrated)
- The reciprocal lattice consists of points which represent diffraction possibilities
- Each point can be labeled with a Miller index
- The units of this lattice are a*, b* and c* and any point can be reached using the vector equation d* = ha* + kb* + lc*



Condition for observing Bragg diffraction



- Diffraction observed when a reciprocal lattice point intersects Ewald sphere
- Crystal rotation brings other lattice points into contact with Ewald sphere
- The vector from origin to lattice point is d* (reciprocal lattice spacing) is red

 it is exactly equal to 1/d and its direction is perpendicular to the hkl plane
- The direction of the diffracted ray is indicated in green



Diffraction measurements



Single crystal diffraction







Powder diffraction in reciprocal space



- Many crystallites with random orientation mean that each reciprocal lattice point will occur in every orientation possible, broadening into the surface of a sphere with radius d*
- The intersection of the Ewald sphere and the reciprocal lattice becomes a cone (intersection of 2 spheres)
- The directions of the vectors are lost and only the lengths of the reciprocal lattice vectors are measurable with powder diffractometers
- 3-D information collapsed into 1-D



Powder diffraction





0 1000 2000 3000 4000 5000 6000 7000 Intensity



Powder diffraction



Typical monochromatic powder diffractometer

- Area or point detector that scans scattering angle, intersecting the Debye-Scherrer cones
- Collapse data into 1-D diffraction pattern





Miller plane equivalence in powder diffraction



All equivalent planes occur at same scattering angle

All planes separated by the same distance occur at one scattering angle in powder diffraction

e.g. (511) and (333) occur at same 2θ for a cubic material



Structure solution and refinement



5.0

6.0

Counts 2.0

1.0

Q-spacing, $Å^{-1}$

2.0

3.0

4.0



Intensity and structure factor

$$|\mathsf{I}_{hkl} \propto |\mathsf{F}_{hkl}|^2$$

Measured intensity proportional to F_{hkl}^2 and so we cannot tell whether F_{hkl} is positive or negative – the Phase problem

$$F_{hkl} \propto \sum f_{i} \exp[2\pi i (hx_{i} + ky_{i} + lz_{i})] \exp(-U_{i}Q^{2}/2)$$

$$f_{i} \text{ is the scattering power (form factor of the ith site i.e. (x_{i},y_{i},z_{i}) and incudes fractional occupancy$$

s Council

See diffraction workshop for details

Aspects influencing diffractometer design



Diffraction at a continous source: ILL



Half of instrument suite are diffractometers



Diffraction at a pulsed source: ISIS



Sans2d Polref Inter Offspec Larmor Wish Mish Larmor Let

Almost half of the instrument suite are diffractometers or carry significant diffraction capability



Moderators

	cold	thermal	hot
moderator	liquid D ₂	Liquid D ₂ O	graphite
moderator temperature	20K	300K	2000K
neutron wavelength	3→20Å	1→3Å	0.3→1Å
sample lengthscale	1Å→100 nm	0.3→5Å	0.1→2Å
sample timescale	1kHz→1 THz	0.1→10 THz	1→100 THz



Designing diffractometers



- Unit cell volume
- Sample environment restrictions
- Need for *in situ* capability
- Sample size
- Sample state

Which come from:

- Science case requirements
- Available budget!



Types of diffractometer

$\lambda = 2dsin\theta$

- Monochromatic (CW)
 - Fix wavelength and scan detector angle
 - Multiple 2θ required to cover Q(d) spacing range
 - Q(d) spacing limit $4\pi/\lambda$ (2π/d)
 - Instrumental count rate factors: Source power, monochromator reflectivity, detector coverage and efficiency, etc
- TOF
 - Fix detector angle and scan wavelength
 - Single 2θ covers range of Q(d) space
 - Q(d range) determined by $\lambda_{\text{max}},\,\lambda_{\text{min}}$ and θ
 - Instrumental count rate factors: Source power, moderator performance, beam transport efficiency, detector coverage and efficiency, etc



Influence of source type on CW or TOF



Some of the neutrons all of the time or all of the neutrons some of the time



Influence of source brightness on CW or TOF



High peak brilliance good for TOF High time-average brilliance good for CW



Instrument layouts



Source

$$L_{1}$$

$$L_{2}$$

$$L_{2}$$

$$L_{2}$$

$$L_{1}$$

$$L_{2}$$

$$2\theta$$

$$Sample$$

$$\lambda = \frac{3956}{v} = \frac{3956 (t-t_{0})}{L_{1}+L_{2}}$$

TOF

 $\Delta \lambda \sim \delta t_0, \delta t, \delta L$

No correlation between λ and θ

Correlation between λ and θ_{B}



Monochromator materials



Choose material and plane to access necessary Q-range Reflectivity falls as wavelength decreases



Q range with monochromators



Shorter wavelengths access higher Q but have lower reflectivity



Higher reflection order contamination



High reflection order contamination complicates analysis with CW data



TOF method










CW or TOF: Q-range summary

For CW:

- For monochromatic instruments the Q_{max} is $4\pi/\lambda$ i.e. when $\sin\theta = 1$, $\theta = 90^{\circ}$, $2\theta = 180^{\circ}$
- If a high Q_{max} is required a shorter wavelength must be used.
- Shorter wavelengths are produced by higher order hkl planes
- Reflectivity is lower for shorter wavelengths
- Realistic Q_{max} of around 25 Å⁻¹

For TOF:

- Q_{max} depends on λ_{min} and detector θ .
- λ_{min} can be much lower than for the CW case allowing $Q_{max} > 100 \text{ Å}^{-1}$
- λ_{min} determined by the moderator, transport characteristics of the guide and which frame the instrument is working in



CW or TOF: Q resolution

Monochromatic

Time-of-flight

$$\frac{\Delta d}{d} = \frac{1}{2} \sqrt{U \cdot \cot^2(\theta) + V \cdot \cot(\theta) + W}$$

- U, V and W are functions of the collimation and U, V also takeoff angle to the monochromator
- Resolution minimum found near the takeoff angle of the monochromator $2\theta_M$
- Higher takeoff angle gives higher resolution for identical wavelength
- Wavelength produced by monochromator is takeoff angle dependent for any particular hkl plane

$$\Delta d_{d} = \left[\Delta \theta^{2} \cot^{2} \theta + \left(\Delta t_{t} \right)^{2} + \left(\Delta L_{t} \right)^{2} \right]^{\frac{1}{2}}$$

- $\Delta \theta$ is the angular uncertainty
- The main component of ∆t is the moderation time of the neutron
- ΔL is the flight path uncertainty of the neutron mainly due to the finite width of the moderator
- First term can be minimised by moving to higher scattering angle
- Second and third terms minimised by increasing instrument length



Number of possible reflections



Reflection density for CW



CW instruments designed to have best resolution at highest peak density



Resolution functions CW v TOF



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high Q caused by moderator residence time

CW Q resolution example



Choose wavelength to match Q resolution required by science in a given Q range



CW or TOF: Q resolution

- CW:
 - Simple, symmetric peakshape function
 - Best resolution where diffraction peak density is highest in scattering angle
 - Different wavelength can be used to give Q resolution where required
 - Different takeoff angle can be used to change resolution function and wavelength
 - Instrument can be high Q resolution but with very limited Q range
- TOF:
 - Complex asymmetric peakshape related to moderator characteristics
 - Instrument length and moderator give wavelength band and overall resolution
 - Q resolution almost constant for a given detector bank so increasing peak density with Q can be an issue
 - Q resolution improved by moving to higher scattering angle detector bank
 - Q range determined by scattering angle of detector bank



Detection efficiency



Neutron Energy (meV)

³He detection efficiency as a function of detection depth. (from Radeka, Neutrons & photon detector workshop, 2012)

https://portal.slac.stanford.edu/sites/conf_public/nxd20 12/presentations/VR_Neutron%20gas%20dets_Aug1_20 12.pdf



Predicted detector efficiency CASCADEdetector for 20¹⁰B layers

http://www.physi.uniheidelberg.de/Forschung/ANP/Cascade/Projekt/resul ts.php?lang=en



Pulsed source availability



Last updated at 13:39:47 Mon 25 Jun

Cycle Availability TS1 86.2% TS2 86.2%

A very good day in terms of beam All experiment types possible





Last updated at 11:57:57 Thu 28 Jun

Cycle Availability TS1 87.6% TS2 87.3%

A good day in terms of beam – still possible issues with *in situ* and time resolved experiments



Pulsed source availability



Last updated at 15:57:20 Tue 19 Jun

Cycle Availability TS1 87.9% TS2 87.8%

A bad day – any time resolved experiment is compromised



CW at a long pulse source: ESS



High peak brilliance good for TOF but also High time-average brilliance good for CW



CW at a long pulse source: ESS





- Use distance to separate higher order monochromator reflections in TOF at the detector
- Develop new monochromator materials
- Access wider Q range
- Tune Q resolution



CW at a long pulse source: ESS



- Combine several current CW instrument capabilities in one simultaneous measurement
- No wavelength contamination
- Lower instrument background
- New science possibilities



Summary: Instrument types

- Reactors build CW instruments*
 - Low peak brilliance, high time-average brilliance
 - Variable reflectivity from monochromators limit low λ use
 - High Q not easily reached
 - Match moderator and monochromator take-off angle to Q range and resolution
 - Beam always on

*Except when significantly restricted geometry constraints from science case necessitate use of TOF

- Pulsed sources build TOF instruments[#]
 - High peak brilliance, low time-averaged brilliance
 - Require efficient beam transport
 - High Q possible
 - Increase instrument length to improve resolution at expense of bandwidth
 - Variable Q range and resolution from detector angles
 - Beam availability can compromise science

[#]Remains to be seen for long pulse sources



Why so many diffractometers?





Single crystal or powder?

Depends on the scientific problem:

- Unambiguous structure determination single crystal
 - Beware extinction and absorption issues
- In situ studies powders
 - Generally the only practical option
- Fast measurements powders
 - Larger samples
- High background materials (such as incoherent scattering) single crystal
 - BUT is possible with powder
- Multi-component systems investigations powder
- Structural phase transitions powder
 - Crystals tend to shatter
- Real systems powders
- Very small samples single crystal
 - Can become difficult to get a powder average



CW or TOF?

Depends on the scientific problem:

- Structure refinement either but TOF preferred as complexity increases
- In situ, time resolved studies CW
- Parametric studies either but CW probably faster for T, P, B mapping
- Fast measurements either (flux for CW, detector coverage for TOF)
- Small samples either (lowest background instrument)
- PDF studies TOF to access high Q
- Magnetic structure CW preferred but TOF catching up
- Polarised neutron work traditionally CW but TOF developing
- Hydrogenous materials CW still preferred but TOF developing
- Large unit cells either source type, but will be Laue methods (quasi-TOF)
- High pressure TOF offers wider Q range, CW higher flux
- Engineering applications either, pick depending on Q range
- Texture either



Instrument examples

- Earliest diffractometers
- Continuous wavelength powder (thermal)
 - High resolution powder
 - High flux powder
 - Variable resolution powder
- Time-of-flight powder
 - High resolution powder
 - Medium resolution powder (×2)
 - Specialised powder
- Single crystal diffractometers



Earliest CW diffractometer





Diffraction instruments at a reactor: ILL



CW, High resolution, thermal powder diffractometers: D1A, D2B



http://www.ill.eu/instrumentssupport/instruments-groups/







Science: Inorganics, small molecule, magnetism, Q range up to about 12 Å⁻¹



CW, High resolution powder diffractometers: D1A, D2B

Instrument	D1A	D2B
Takeoff angle / °	122	135
Flux / n cm ⁻² s ⁻¹	10 ⁶	10 ⁶ to 10 ⁷
Beam (h × w) / mm	30 × 20	50 × 20
Detectors	25 ³ He × 10 cm h	128 ³ He × 30 cm h
Wavelengths	Ge(hhl)	Ge(hhl)
Δd/d Resolution	$2-3 \times 10^{-3}$	Min 5 × 10 ⁻⁴
Background	Very Low (60 m)	Low (15 m)
Average data collection	3-24 hrs	0.25-4 hrs
time		

Similar instruments at all continuous sources: Echidna (ANSTO), Spodi (FRM-II), BT-1 (NIST), 3T2 (LLB), HB-2A (HFIR) etc...

http://www.ill.eu/instrumentssupport/instruments-groups/



CW, High flux, thermal powder diffractometers: D1B, D20















CW, High flux, thermal powder diffractometers: D1B, D20

Instrument	D1B (old) / D1B (new)	D20
Takeoff angle / °	44	28, 42 (±2)
Flux / n cm ⁻² s ⁻¹	6.5 × 10 ⁶ HOPG(002) 0.4 × 10 ⁶ Ge(311)	4.2 × 10 ⁷ HOPG(002) 9.8 × 10 ⁷ Cu(200) 42° 3.2 × 10 ⁷ Cu(200) 28°
Beam (h × w) / mm	50 × 20	50 × 20
Detectors	80° multi-wire / 128° multi-wire 0.2° separation / 0.1° separation 400 channels / 1280 channels	153.6° micro-strip detector 0.1° separation 1536 channels
Wavelengths / Å	2.52, 1.28	2.42, 1.30, 0.87
Δd/d Resolution	> 1 × 10 ⁻²	> 1 × 10 ⁻²
Background	Medium (low with ROC)	Medium/High (low with ROC)
Average data collection time	5-10 mins / 1-5 mins	<1 min

Fewer comparable instruments: Wombat (ANSTO), G4.1 (LLB), HB-2C (HFIR)



CW, variable resolution, thermal powder diffractometer: D20



120°







90°



65°





42°

28°

Photos courtesy T. Hansen ILL

CW, variable resolution, thermal powder diffractometer: D20

Instrument	D20 (high flux)	D20 (high takeoff angle)
Takeoff angle / °	28, 42 (±2)	65, 90, 120 (±2)
Flux / n cm ⁻² s ⁻¹	4.2 × 10 ⁷ HOPG(002) 9.8 × 10 ⁷ Cu(200) 42° 3.2 × 10 ⁷ Cu(200) 28°	8.0 × 10 ⁶ Ge(115) 7.5 × 10 ⁶ Ge(117) 4.0 × 10 ⁶ Ge(119)
Beam (h × w) / mm	50 × 20	50 × 20
Detectors	153.6° micro-strip detector 0.1° separation 1536 channels	153.6° micro-strip detector 0.1° separation 1536 channels
Wavelengths / Å	2.42, 1.30, 0.87	variable 0.8-3 Ge(hhl/00l/hhh)
∆d/d Resolution	> 1 × 10 ⁻²	See next slide
Background	Medium/High (low with ROC)	Medium/High (low with ROC)
Average data collection time	<1 min	5-15 mins (30 times faster than simila counting statistics on D2B)

Even fewer contemporary instruments: HRPT (PSI), Wombat (ANSTO has potential)



Tune resolution using θ_B





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SIS

Low θ_{B} v high θ_{B} : Q resolution v count-rate



Parasitic scattering on instruments with area detectors: D20 collimator



Parasitic scattering on instruments with area detectors: D20 example



CW single crystal diffraction







- Monochromatic and Laue type instruments are represented
- Q-range of interest and unit cell volume determine whether hot, thermal or cold neutron spectrum required for both instrument types



LADI-III

CYCLOPS



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http://www.ill.eu/instrumentssupport/instruments-groups/
Pulsed source: ISIS





GEM: high intensity powder diffraction



GEM: high intensity powder diffraction





Initially constructed in the late 1990s this powder/liquids diffractometer hybrid changed the way TOF diffraction instruments were designed and built

http://wwwisis2.isis.rl.ac.uk/disordered/gem/gem_home.htm



GEM: high intensity powder diffraction

Detector Bank	Scattering angle 2θ (deg)	Range in azimuthal angle ϕ (deg)	Secondary flight path L_2 (m)	Number of detector elements/ modules	Solid angle Ω (sr)	Resolution $\Delta Q/Q(\%)$	Minimum accessible momentum transfer Q_{min} (Å ⁻¹)
Bank0	1.21-3.18	±90.0	2.757–2.767	80/4	0.008	5–10	0.04
Bank1	5.32-12.67	±45.0	2.365-2.376	330/6	0.056	4.7	0.17
Bank2	13.44-21.59	± 43.4	1.477-2.100	320/4	0.093	2.4	0.43
Bank3	24.67-45.61	± 42.5	1.077-1.893	900/10	0.478	1.7	0.79
Bank4	50.07-74.71	±44.4	1.028-1.436	1400/14	0.988	0.79	1.56
Bank5	79.07-106.60	± 44.5	1.376-1.383	2160/18	1.135	0.51	2.35
Bank5X	106.02-114.19	±42.7	1.377-1.387	720/18	0.378	0.5	2.95
Bank6	142.50-149.72	± 69.3	1.544-1.738	560/14	0.280	0.34	3.50
Bank7	149.98-171.40	± 66.6	1.035-1.389	800/10	0.443	0.35	3.57







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From Hannon, NIMA (2005), 551, 88-107

Polaris: high intensity powder diffraction



Polaris: old configuration





Compare with GEM:

- Higher sample flux
- Wider bandwidth
- Lower resolution
- Hotter spectrum
- Lower detector coverage

http://www.isis.stfc.ac.uk/instruments/polaris/polaris4643.html



Polaris: old configuration

bank position	low angle	low angle	backscattering	90 degrees
(label)	(A)	(B)	(C)	(E)
detector type	³ He	ZnS	³ He	ZnS
no. of elements	2 x 40 = 80	4 x 20 = 80	2 x 29 = 58	6 x 36 = 216
L ₂ (m)	1.72 - 2.65	~2.2	0.65 - 1.35	~0.80
20 range	28°< 2θ < 42°	13°< 2θ < 15°	130°< 2θ < 160°	83°< 2θ < 97°
Ω (ster)	0.046	0.009	0.29	0.48
∆d/d	~1x10 ⁻²	~3x10 ⁻²	~5x10⁻³	~7x10 ⁻³
d-range (Å)	0.5 - 8.3	0.5 - 21.6	0.2 - 3.2	0.2 - 4.0
Q-range (Å ⁻¹)	0.75 - 12.6	0.3 - 12.6	2.0 - 31.4	1.5 - 31.4

- Good workhorse instrument for powder diffraction
- High Q accessible for disordered materials investigation using the PDF method
- Some in situ capability but limited by count-rate
- Compatible with a wide range of restricted geometry sample environment



Polaris upgrade



- Increase primary flight path to 14 m
- Optimise each detector bank to give constant resolution
- Increase detector coverage
- Design a collimator to reduce background and parasitic scattering

http://www.isis.stfc.ac.uk/instruments/polaris/polaris-upgrade-poster11575.pdf





Polaris upgrade



http://www.isis.stfc.ac.uk/instruments/polaris/p olaris4643.html



Current Polaris

http://www.isis.stfc.ac.uk/instruments/polaris/polaris-upgrade---first-diffraction-pattern12763.pdf



- Increased count rate ×3 at high scattering angle to >20 for low angle banks
- Resolution improvement e.g. bank 5 and 6 of 3 \times 10⁻³ cf. 5 \times 10⁻³
- Improvement in data at high Q



Polaris 1995 v 2013





- 1995 500 mg 24+ hrs
- 2013 500 mg 15-20 minutes with increased Q-range

Contemporary instruments NOVA and iMateria (J-PARC), POWGEN-3 (SNS)



Polaris: pushing boundaries in sample size



~1mm³ sample of NaNiF₃ phase prepared at high p + high T

Lindsay-Scott et al, J. Appl. Cryst., 47, 1939 (2014)



HRPD: high resolution powder diffraction



HRPD: high resolution powder diffraction



http://www.isis.stfc.ac.uk/instruments/hrpd/hrpd.html



HRPD: high resolution powder diffraction

Table 1. HRPD Detector Bank Details							
	Backscattering	90°	Low Angle				
Detector Specification	ZnS scintillator	ZnS scintillator	½" 10atm He ³ gas tubes				
Geometry	60 rings: $7 < r_1 < 8.5$ cm $35.5 < r_{60} < 37$ cm 8 Octants: 4147cm ²	Slab: 20 x 20cm 66 x 3mm elements 6 Modules: 2400cm ²	72 tubes: (20cm active length) 8 tubes/module 9 Modules: 1800cm ²				
Fixed Scattering Angle	160° < 2θ < 176° (1m)	87° < 2θ < 93°	28° < 2θ < 32°				
Solid Angle (Ω)	0.41 ster (1m)	0.08 ster	0.01 ster				
Resolution (∆d/d)	~ 4-5 x 10 ⁻⁴	~ 2 x 10 ⁻³	~ 2 x 10 ⁻²				
d -spacing range (30- 230ms)	~0.6 - 4.6Å 0.25 – 4.6 Å	~0.9 - 6.6Å 0.4 – 6.6 Å	~ 2.2 - 16.5Å 1.0 – 16.5 Å				

- Large backscattering detector to minimise cot²θ in resolution term
- High resolution at intermediate Q
- Long flight path to reduce
 Δt/t and ΔL/L uncertainties
- Pulse skipping to increase bandwidth (@50 Hz 0.4 Å)
- Good combination of parameters for a high resolution TOF diffractometer



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Contemporary instrument sHRPD (J-PARC), no current analogue at SNS

PEARL: high pressure diffraction



PEARL: high pressure diffraction



Instrument geometry designed to match sample environments



PEARL: high pressure diffraction



(a) (b) WC seat (transverse) Anvil core 0 Diffracted beam Steel support ring Incident beam B₄C layer (longitudinal) 'Peashooter Gd foil Seat Thrust direction Incident beam (transverse) (c) (d) — ZTA 0.25 — WC mm WC(+Ni coefficient / 0.20 Intensity SD(+Co 0.15 Attenuation c 0.00 DC25 ZTA 0.00 0.5 2.0 2.5 1.0 1.5 0.0 1.0 2.0 3.0 4.0 5.0 6.0 λ/Å d-spacing / Å

Steel-fretted

Exit beam

Anvil material properties

Paris Edinburgh V3 press

See C.L. Bull, N.P Funnell, M.G. Tucker, S. Hull, D.J. Francis, W.G. Marshall, *High Pressure Research* 2016, DOI: 10.1080/08957959.2016.1214730

Contemporary instruments: Planet(J-Parc), SNAP (SNS)



ENGIN-X: engineering diffraction



ENGIN-X: engineering diffraction



Contemporary instruments: Vulcan (SNS)



INES: joint CNR-ISIS instrument



INES for cultural heritage



General purpose diffractometer for materials characterisation and cultural heritage studies. Built and managed by the Italian National Research Council (CNR) within a co-operation agreement with STFC.



IMAT: imaging and diffraction



IMAT: imaging and diffraction

Dual-use instrument: neutron imaging and diffraction

- Conventional neutron radiography and tomography
- Novel energy-selective (Bragg-edge) imaging techniques
- Simultaneous strain and texture measurements





WISH: magnetic diffraction



WISH: magnetic diffraction

The magnetic moment of the neutron interacts with magnetic fields caused, for example, by unpaired electron spins in a material.





WISH: Magnetic diffraction



See Chapon et al. Neutron News (2011), 22(2), 22-25



SXD: single crystal diffraction



- chemical crystallography
- Q space mapping
- incommensurate structures
- high pressure



TOF Laue method

SXD uses the 'time-of-flight Laue' method to scans a large volume of reciprocal space at each crystal orientation.







SXD: single crystal diffraction









SXD: single crystal diffraction

- H₂O moderator poisoned at 2 cm
- 0.2 10 Å wavelength band
- Primary flight path 8.3 m
- Beam size < 15 mm
- Eleven 192 × 192 mm² detectors (3 × 3 mm² resolution)



Unlike an image plate set-up the detectors are continuously read-out as a function of TOF allowing spatial overlap to be resolved in the TOF channel while minimising background

Keen et al. J. Appl. Cryst. (2006), 39, 714-722) http://www.isis.stfc.ac.uk/instruments/sxd/sxd4813.html

Contemporary instruments: Topaz (SNS), Senju (J-Parc), Mandi (SNS)



Why so many diffractometers?

Q(d) Resolution



Diffractometer design: final words

Define a science case!!

Instruments are designed and built to perform science The science case determines requirements Instruments are designed and constructed to meet those requirements

